

General Description

IRF840 the silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

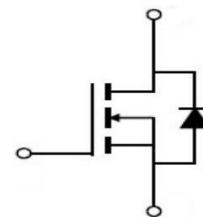
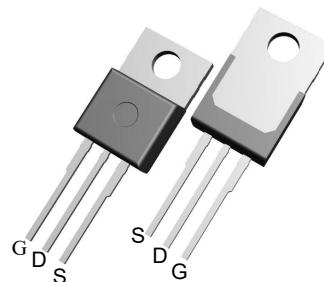


Features

V _{DSS}	500	V
I _D	10	A
P _D (T _C =25°C)	50	W
R _{DS(ON)} (at V _{GS} =10V)	<0.7	Ω

Application

- Battery protection
- Load switch
- Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
IRF840	TO-220	IRF840	1000

Absolute Maximum Ratings (T_C=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{DSS}	Drain-Source Voltage	500	V
I _D	Drain Current	T _j =25°C	10.0
		T _j =100°C	5.7
V _{GSS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy (note1)	190	mJ
I _{AR}	Avalanche Current (note2)	10.0	A
P _D	Power Dissipation (T _j =25°C)	50	W
T _j	Junction Temperature(Max)	150	°C
T _{stg}	Storage Temperature	-55~+150	°C
T _L	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
R _{θJC}	Thermal Resistance,Junction to Case	-	1.88	°C/W
R _{θJA}	Thermal Resistance,Junction to Ambient	-	62.5	°C/W

Electrical Characteristics at $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Condition	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250 \mu\text{A}, \text{VGS}=0$	500	--	--	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Conficient	$\text{ID}=250 \mu\text{A}, \text{Reference to } 25^\circ\text{C}$	--	0.55	--	V/ $^\circ\text{C}$
IDSS	Zero Gate Voltage Drain Current	$\text{Vds}=500\text{V}, \text{Vgs}=0\text{V}$	--	--	1	μA
		$\text{Vds}=400\text{V}, \text{Tc}=125^\circ\text{C}$			10	μA
IGSSF	Gate-body leakage Current, Forward	$\text{Vgs}=+30\text{V}, \text{Vds}=0\text{V}$	--	--	100	nA
IGSSR	Gate-body leakage Current,	$\text{Vgs}=-30\text{V}, \text{Vds}=0\text{V}$	--	--	-100	nA
On Characteristics						
$\text{V}_{\text{GS(th)}}$	Date Threshold Voltage	$\text{Id}=250\mu\text{A}, \text{Vds}=\text{Vgs}$	2	--	4	V
$\text{R}_{\text{DS(on)}}$	Static Drain-Source	$\text{Id}=4.5\text{A}, \text{Vgs}=10\text{V}$	--	0.65	0.70	Ω
Dynamic Characteristics						
Ciss	Input Capacitance	$\text{VDS}=25\text{V}, \text{VGS}=0, \text{f}=1.0\text{MHz}$	--	1012	--	pF
Coss	Output Capacitance		--	160	--	pF
Crss	Reverse Transfer Capacitance		--	20	--	pF
Switching Characteristics						
Td(on)	Turn-On Delay Time	$\text{VDD}=250\text{V}, \text{ID}=10\text{A}, \text{RG}=25\Omega$ (Note 3,4)	--	25	60	nS
Tr	Turn-On Rise Time		--	95	200	nS
Td(off)	Turn-Off Delay Time		--	55	120	nS
Tf	Turn-Off Fall Time		--	60	130	nS
Qg	Total Gate Charge	$\text{VDS}=400, \text{VGS}=10\text{V}, \text{ID}=10\text{A}$ (Note 3,4)	--	28	36	nC
Qgs	Gate-Source Charge		--	7	--	nC
Qgd	Gate-Drain Charge			12.5	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximun Continuous Drain-Source Diode Forward Current		--	--	9	A
I_{SM}	Maximun Plused Drain-Source DiodeForwad Current		--	--	36	A
V_{SD}	Drain-Source Diode Forward	$\text{Id}=10\text{A}$	--	--	1.45	V
trr	Reverse Recovery Time	$\text{Is}=10.0\text{A}, \text{VGS}=0\text{V}$ $d\text{I}/dt=100\text{A}/\mu\text{s}$ (Note3)	--	300	--	nS
Qrr	Reverse Recovery Charge		--	2.2	--	μC

*Notes 1, L=8mH, IAS=10 A,VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

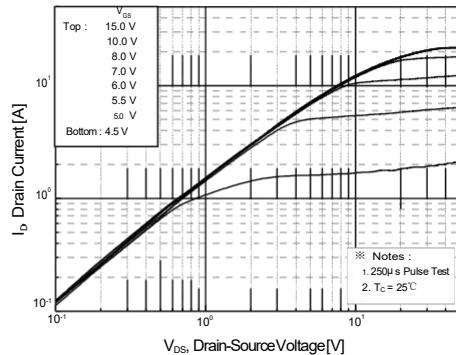


Figure 1. On-Region Characteristics

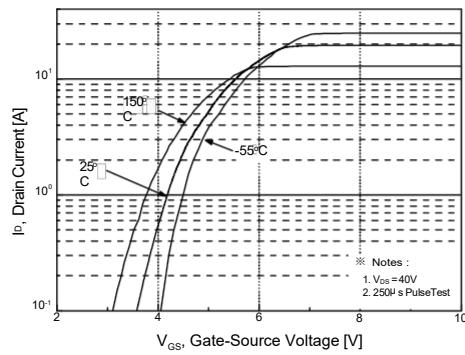


Figure 2. Transfer Characteristics

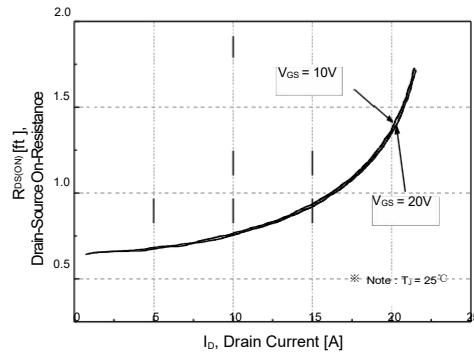


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

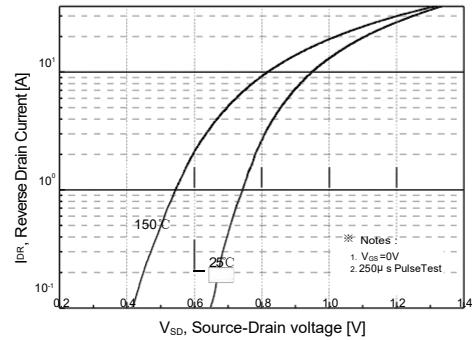


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

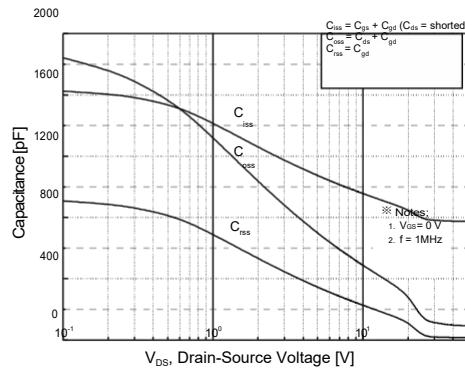


Figure 5. Capacitance Characteristics

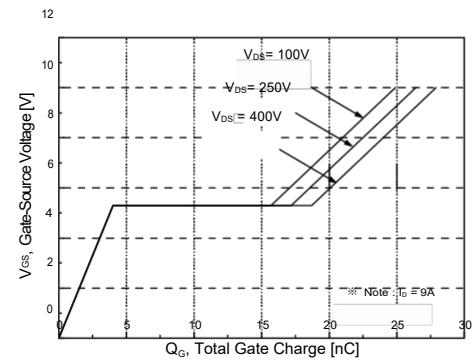
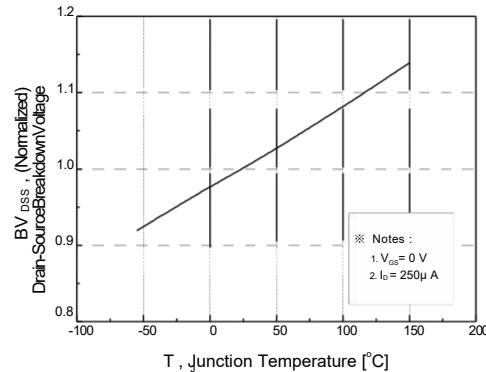
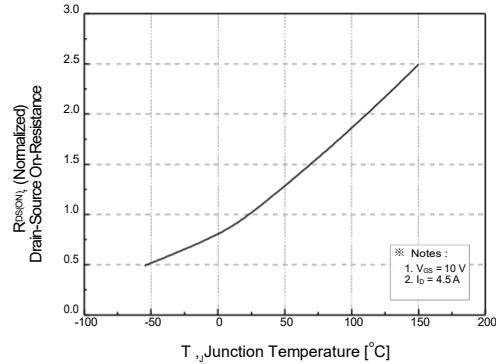


Figure 6. Gate Charge Characteristics



**Figure 7. Breakdown Voltage Variation
vs Temperature**



**Figure 8. On-Resistance Variation
vs Temperature**

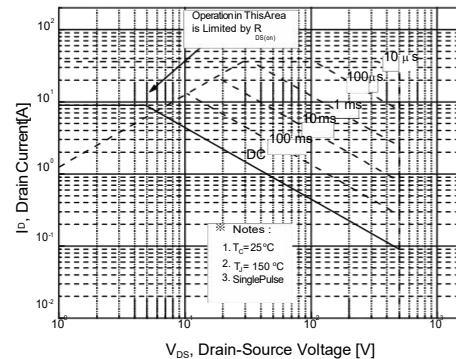
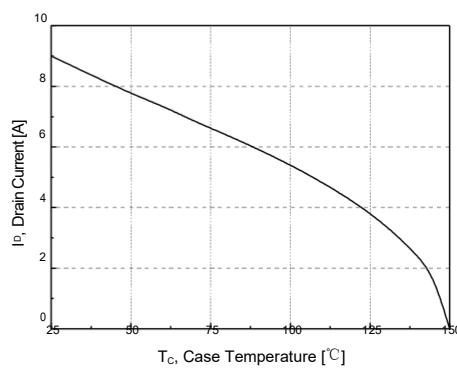


Figure 9-2. Maximum Safe Operating Area



**Figure 10. Maximum Drain Current
vs Case Temperature**

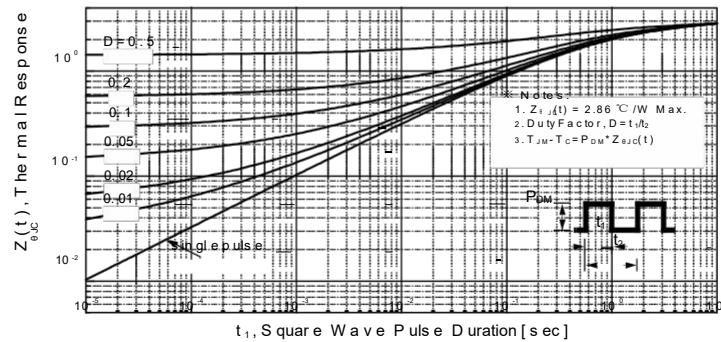
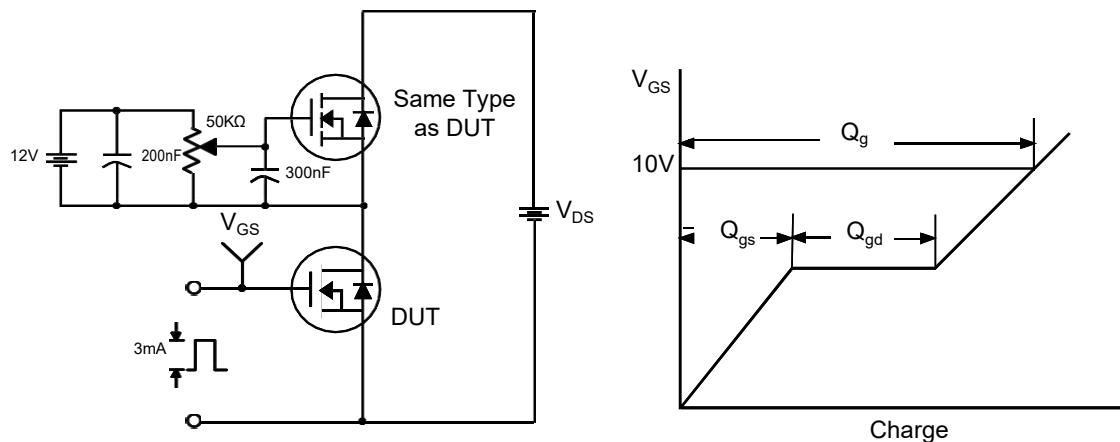
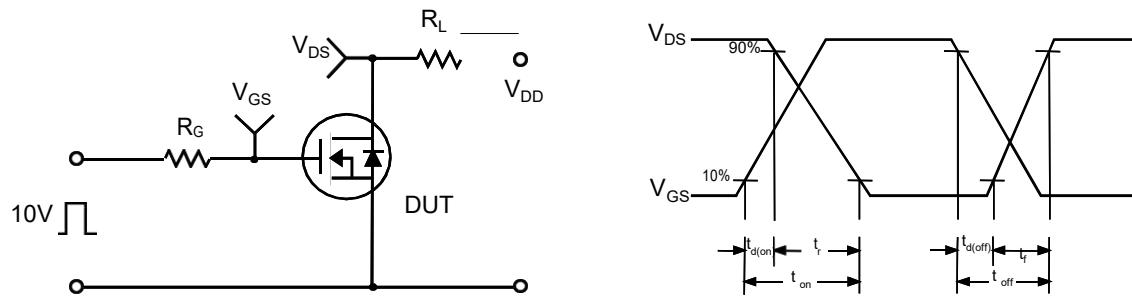


Figure 11-2. Transient Thermal Response Curve

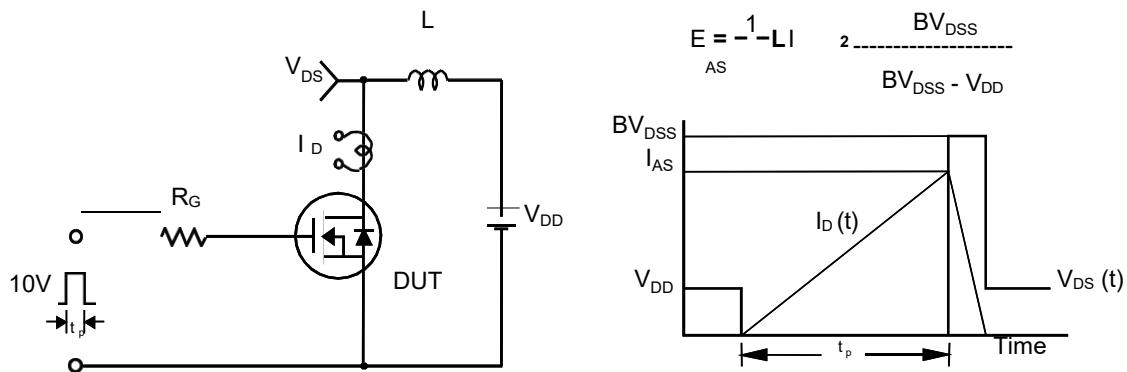
Gate Charge Test Circuit & Waveform

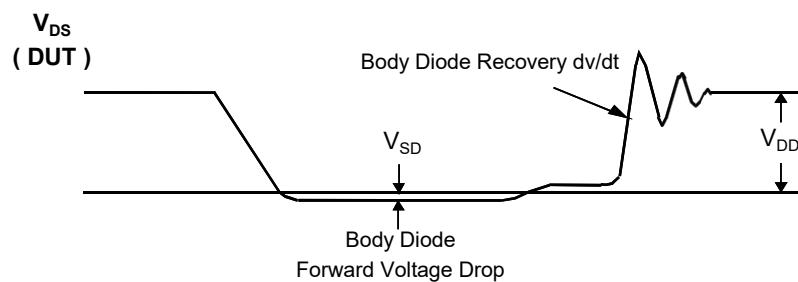
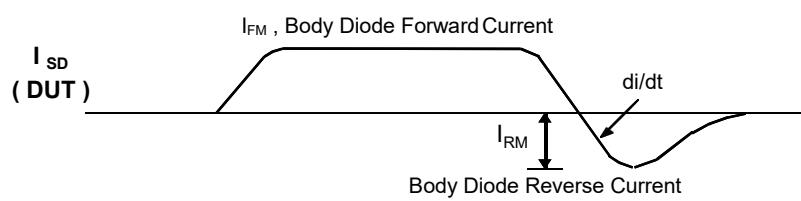
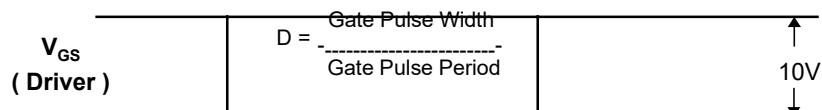
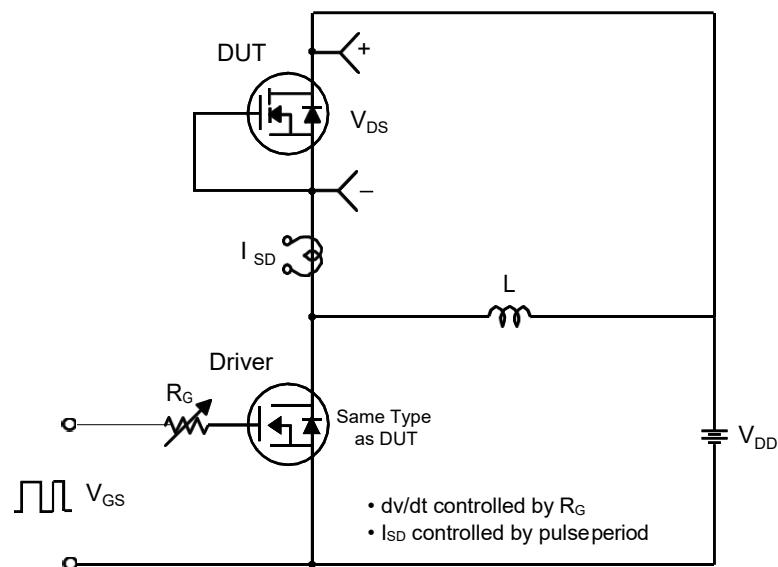


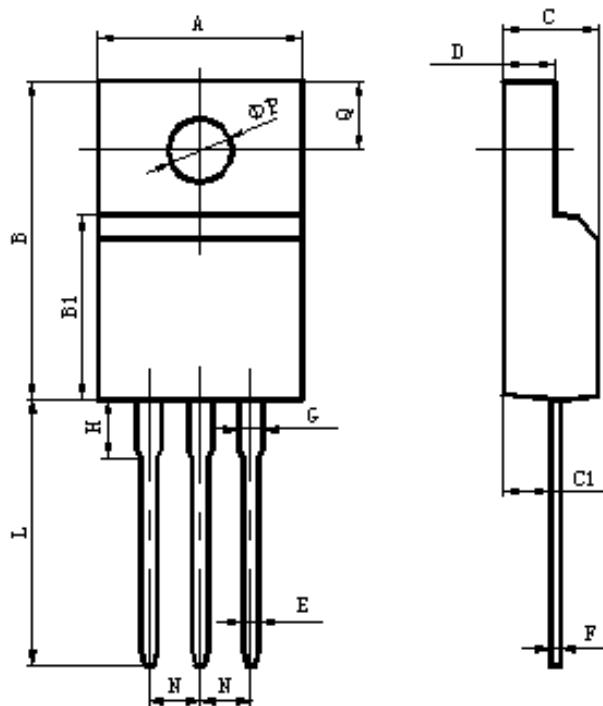
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms


Package Mechanical Data-TO-220 Single


Items	Values(mm)	
	MIN	MAX
A	9.60	10.4
B	15.4	16.2
B1	8.90	9.50
C	4.30	4.90
C1	2.10	3.00
D	2.40	3.00
E	0.60	1.00
F	0.30	0.60
G	1.12	1.42
H	3.40	3.80
	2.40	2.90
L*	12.0	14.0
N	2.34	2.74
Q	3.15	3.55
Φ P	2.90	3.30